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Maximum-likelihood estimation in ptychography in the presence of Poisson–Gaussian noise statistics: publisher’s note

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In the caption for Fig. 1 in [1], the term “grayscale” was misspelled as “grsyscale.” The article was corrected online on 16 November 2023.

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REFERENCES

1. J. Seifert, Y. Shao, R. van Dam, *et al.*, *Opt. Lett.* **48**, 6027 (2023).